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500V, 38A, 0.10Ω Max, t<sub>rr</sub> ≤280ns

# N-Channel FREDFET

Power MOS 8  $^{\text{Im}}$  is a high speed, high voltage N-channel switch-mode power MOSFET. This 'FREDFET' version has a drain-source (body) diode that has been optimized for high reliability in ZVS phase shifted bridge and other circuits through reduced  $t_{\text{FT}}$ , soft recovery, and high recovery dv/dt capability. Low gate charge, high gain, and a greatly reduced ratio of  $C_{\text{FSS}}/C_{\text{iss}}$  result in excellent noise immunity and low switching loss. The intrinsic gate resistance and capacitance of the poly-silicon gate structure help control di/dt during switching, resulting in low EMI and reliable paralleling, even when switching at very high frequency.



Single die FREDFET

# ET G

#### **FEATURES**

- · Fast switching with low EMI
- · Low trr for high reliability
- Ultra low C<sub>rss</sub> for improved noise immunity
- · Low gate charge
- · Avalanche energy rated
- RoHS compliant

#### **TYPICAL APPLICATIONS**

- · ZVS phase shifted and other full bridge
- · Half bridge
- · PFC and other boost converter
- Buck converter
- · Single and two switch forward
- Flyback

#### **Absolute Maximum Ratings**

Symbol	Parameter	Ratings	Unit
L	Continuous Drain Current @ T <sub>C</sub> = 25°C	38	
'D	Continuous Drain Current @ T <sub>C</sub> = 100°C	24	А
I <sub>DM</sub>	Pulsed Drain Current <sup>①</sup>	175	
V <sub>GS</sub>	Gate-Source Voltage	±30	٧
E <sub>AS</sub>	Single Pulse Avalanche Energy ©	1200	mJ
I <sub>AR</sub>	Avalanche Current, Repetitive or Non-Repetitive	28	А

#### **Thermal and Mechanical Characteristics**

Symbol	Characteristic		Тур	Max	Unit	
P <sub>D</sub>	Total Power Dissipation @ T <sub>C</sub> = 25°C			355	W	
$R_{\theta JC}$	Junction to Case Thermal Resistance			0.35	0.35 °C/W	
R <sub>ecs</sub>	Case to Sink Thermal Resistance, Flat, Greased Surface		0.15			
$T_J$ , $T_{STG}$	Operating and Storage Junction Temperature Range -5:			150	°C	
V <sub>Isolation</sub>	RMS Voltage (50-60hHz Sinusoidal Waveform from Terminals to Mounting Base for 1 Min.) 2500				V	
W <sub>T</sub>	Package Weight		1.03		OZ	
			29.2		g	
Torque	Terminals and Mounting Screws.		·	10	in∙lbf	
				1.1	N·m	

Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
V <sub>BR(DSS)</sub>	Drain-Source Breakdown Voltage	$V_{GS} = 0V, I_{D} = 250 \mu A$	500			V
$\Delta V_{BR(DSS)} / \Delta T_{J}$	Breakdown Voltage Temperature Coefficient	Reference to 25°C, I <sub>D</sub> = 25	0μΑ	0.60		V/°C
R <sub>DS(on)</sub>	Drain-Source On Resistance <sup>③</sup>	V <sub>GS</sub> = 10V, I <sub>D</sub> = 28A		0.085	0.10	Ω
V <sub>GS(th)</sub>	Gate-Source Threshold Voltage	\/ =\/   = 2.5m/	2.5	4	5	V
$\Delta V_{GS(th)}/\Delta T_{J}$	Threshold Voltage Temperature Coefficient	$V_{GS} = V_{DS}, I_D = 2.5 \text{mA}$	`	-10		mV/°C
	Zero Gate Voltage Drain Current	$V_{DS} = 500V$ $T_J = 25^{\circ}C$			250	μA
DSS		$V_{GS} = 0V$ $T_J = 125^\circ$	С		1000	μA
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> = ±30V			±100	nA

## **Dvnamic Characteristics**

### T<sub>1</sub> = 25°C unless otherwise specified

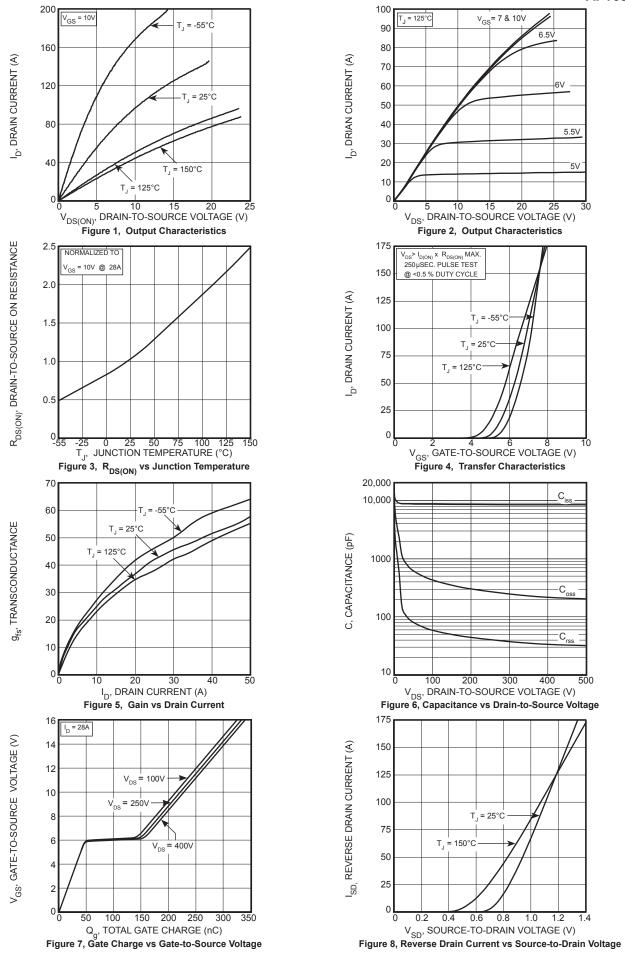
Symbol	Parameter	Test Conditions	Min	Тур	Max	Unit
g <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> = 50V, I <sub>D</sub> = 28A		42		S
C <sub>iss</sub>	Input Capacitance	V 0V V 05V		8800		
C <sub>rss</sub>	Reverse Transfer Capacitance	$V_{GS} = 0V, V_{DS} = 25V$ f = 1MHz		120		
C <sub>oss</sub>	Output Capacitance	1 111112		945		
$C_{o(cr)} @$	Effective Output Capacitance, Charge Related	V = 0V V = 0V+c 222V		550		pF
C <sub>o(er)</sub> ⑤	Effective Output Capacitance, Energy Related	V <sub>GS</sub> = 0V, V <sub>DS</sub> = 0V to 333V		275		
$Q_g$	Total Gate Charge	)/ 01×40)/ 1 00A		220		
$Q_{gs}$	Gate-Source Charge	$V_{GS} = 0 \text{ to } 10V, I_{D} = 28A,$ $V_{DS} = 250V$		50		nC
$Q_{gd}$	Gate-Drain Charge	V <sub>DS</sub> = 250V		100		
t <sub>d(on)</sub>	Turn-On Delay Time	Resistive Switching		38		
t <sub>r</sub>	Current Rise Time	V <sub>DD</sub> = 333V, I <sub>D</sub> = 28A		45		ns
t <sub>d(off)</sub>	Turn-Off Delay Time	$R_{G} = 4.7\Omega^{\textcircled{6}}, V_{GG} = 15V$		100		115
t <sub>f</sub>	Current Fall Time	]		33		

**Source-Drain Diode Characteristics** 

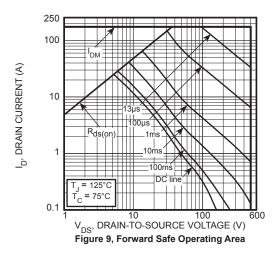
Symbol	Parameter	Test Condit	Min	Тур	Max	Unit	
I <sub>s</sub>	Continuous Source Current (Body Diode)	MOSFET symbol showing the integral reverse p-n	OD D			38	А
I <sub>SM</sub>	Pulsed Source Current (Body Diode) <sup>①</sup>	junction diode (body diode)	s s			175	^
V <sub>SD</sub>	Diode Forward Voltage	$I_{SD} = 28A, T_{J} = 25^{\circ}C, V_{GS} = 0V$				1.2	V
t <sub>rr</sub>	Reverse Recovery Time		T <sub>J</sub> = 25°C			280	ns
, LL			T <sub>J</sub> = 125°C			520	7 115
Q <sub>rr</sub>	Reverse Recovery Charge	I <sub>SD</sub> = 28A <sup>③</sup>	T <sub>J</sub> = 25°C		1.20		μC
		di <sub>SD</sub> /dt = 100A/µs	T <sub>J</sub> = 125°C		3.07		μΟ
	Reverse Recovery Current	$V_{DD} = 100V$ $T_{J} = 25^{\circ}C$ $T_{J} = 125^{\circ}C$	T <sub>J</sub> = 25°C		10.1		Α
'rrm			T <sub>J</sub> = 125°C		14.5		] ^
dv/dt	Peak Recovery dv/dt	I <sub>SD</sub> ≤ 28A, di/dt ≤1000A/µs, V <sub>DD</sub> = 333V, T <sub>J</sub> = 125°C				20	V/ns

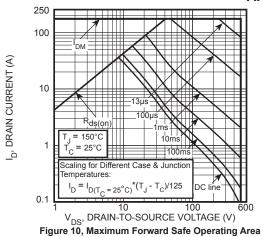
- ① Repetitive Rating: Pulse width and case temperature limited by maximum junction temperature.
- ② Starting at T  $_{\rm J}$  = 25°C, L = 3.06mH, R  $_{\rm G}$  = 25 $\Omega$ , I  $_{\rm AS}$  = 28A.
- ③ Pulse test: Pulse Width < 380μs, duty cycle < 2%.
- $\bigcirc$  C<sub>o(cr)</sub> is defined as a fixed capacitance with the same stored charge as C<sub>OSS</sub> with V<sub>DS</sub> = 67% of V<sub>(BR)DSS</sub>. (a) C<sub>o(er)</sub> is defined as a fixed capacitance with the same stored energy as C<sub>OSS</sub> with V<sub>DS</sub> = 67% of V<sub>(BR)DSS</sub>. To calculate C<sub>o(er)</sub> for any value of  $V_{DS}$  less than  $V_{(BR)DSS}$ , use this equation:  $C_{o(er)}$  = -2.04E-7/ $V_{DS}$ ^2 + 4.76E-8/ $V_{DS}$  + 1.36E-10.
- ⑥ R<sub>G</sub> is external gate resistance, not including internal gate resistance or gate driver impedance. (MIC4452)

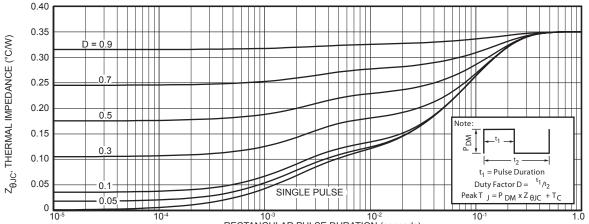
Microsemi reserves the right to change, without notice, the specifications and information contained herein.



050-8130 Rev D 8-20







RECTANGULAR PULSE DURATION (seconds)
Figure 11. Maximum Effective Transient Thermal Impedance Junction-to-Case vs Pulse Duration

#### SOT-227 (ISOTOP®) Package Outline

